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Application/Control No.	Applicant(s)/Patent under Reexamination
10/766,322	MIYA ET AL.

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Examiner	
Jay M. Patidar	

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324	207.18	6/12/2006	JP	
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INTERFERENCE SEARCHED				
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324	207.18	6/12/2006	JP	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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